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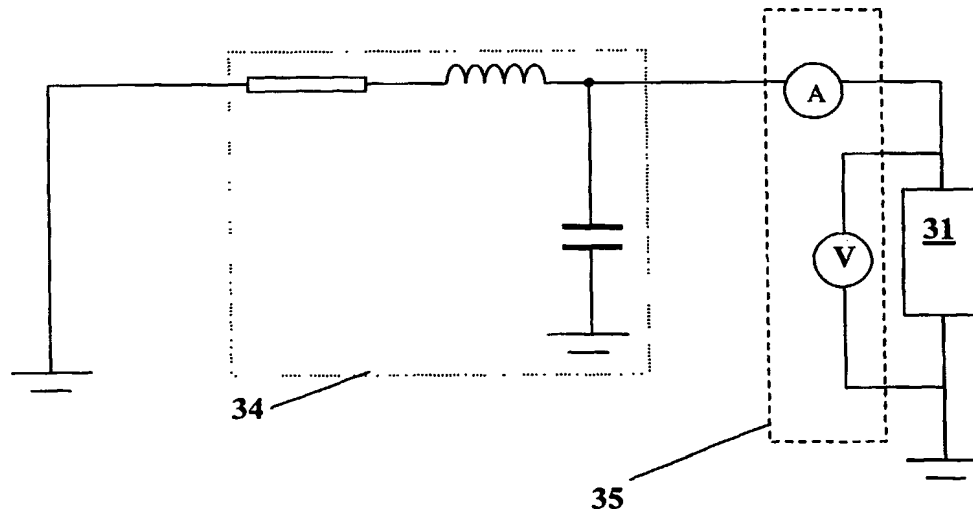
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(54) Title: SEMICONDUCTOR MONITORING INSTRUMENT



(57) **Abstract:** An instrument for measuring dynamic I-V conduction characteristics of a semiconductor device-under-test is provided with a means to apply an adjustable bias at both the input and the output of a device-under-test having the form of fast, superimposed generally rectangular bipolar pulses, optionally provided with a means to measure do I-V conduction characteristics of a semiconductor device-under-test by applying a do signal at both the input and the output of the device-under-test, and provided with a means to measure the current response thereto at both input and output. A method of measure dynamic I-V conduction characteristics of a semiconductor device-under-test is also described.

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